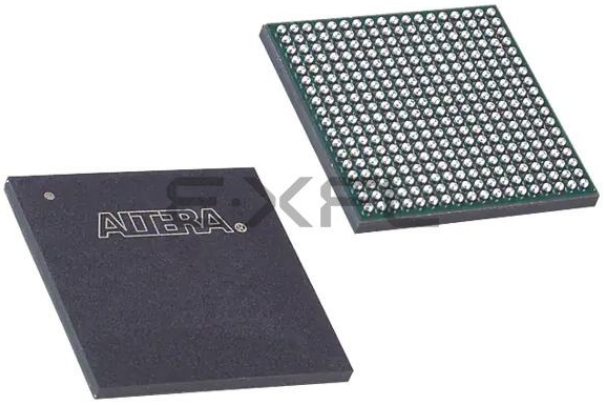

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	2006
Number of Logic Elements/Cells	20060
Total RAM Bits	294912
Number of I/O	233
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	324-BGA
Supplier Device Package	324-FBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c20f324c6n

Table 1–1. Cyclone Device Features (Part 2 of 2)

Feature	EP1C3	EP1C4	EP1C6	EP1C12	EP1C20
Total RAM bits	59,904	78,336	92,160	239,616	294,912
PLLs	1	2	2	2	2
Maximum user I/O pins *(1)*	104	301	185	249	301

Note to Table 1–1:
(1) This parameter includes global clock pins.

Cyclone devices are available in quad flat pack (QFP) and space-saving FineLine® BGA packages (see Tables 1–2 through 1–3).

Table 1–2. Cyclone Package Options and I/O Pin Counts

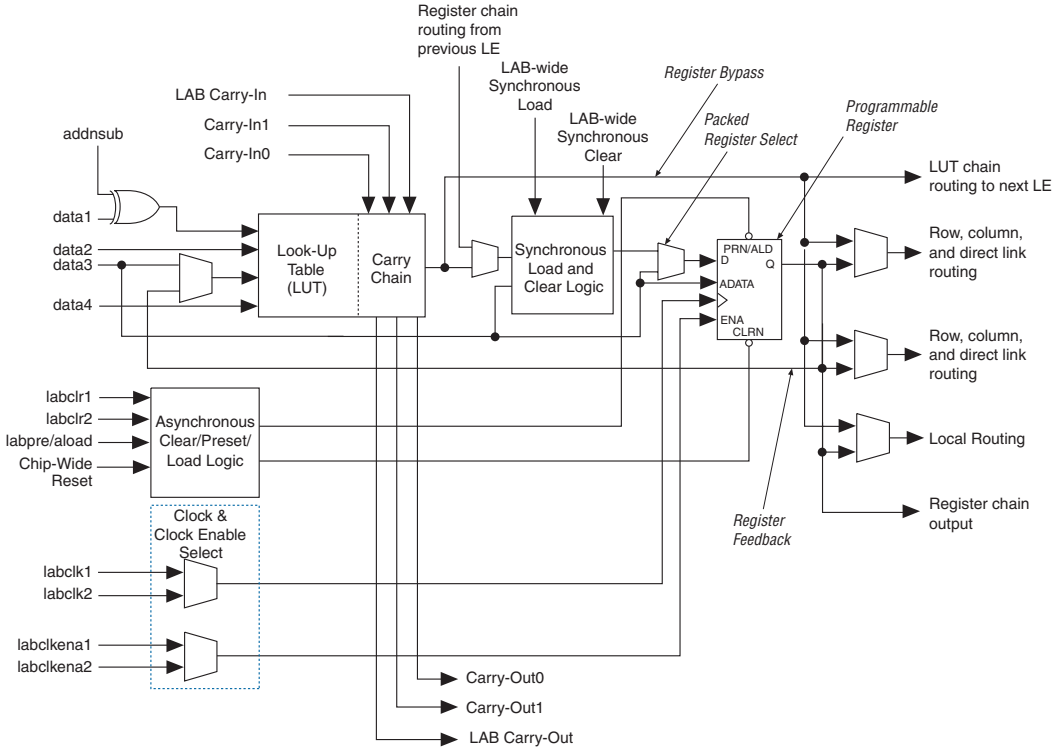
Device	100-Pin TQFP *(1)*	144-Pin TQFP *(1), (2)*	240-Pin PQFP *(1)*	256-Pin FineLine BGA	324-Pin FineLine BGA	400-Pin FineLine BGA
EP1C3	65	104	—	—	—	—
EP1C4	—	—	—	—	249	301
EP1C6	—	98	185	185	—	—
EP1C12	—	—	173	185	249	—
EP1C20	—	—	—	—	233	301

Notes to Table 1–2:
(1) TQFP: thin quad flat pack.
PQFP: plastic quad flat pack.
(2) Cyclone devices support vertical migration within the same package (i.e., designers can migrate between the EP1C3 device in the 144-pin TQFP package and the EP1C6 device in the same package).

Vertical migration means you can migrate a design from one device to another that has the same dedicated pins, JTAG pins, and power pins, and are subsets or supersets for a given package across device densities. The largest density in any package has the highest number of power pins; you must use the layout for the largest planned density in a package to provide the necessary power pins for migration.

For I/O pin migration across densities, cross-reference the available I/O pins using the device pin-outs for all planned densities of a given package type to identify which I/O pins can be migrated. The Quartus® II software can automatically cross-reference and place all pins for you when given a device migration list. If one device has power or ground pins, but these same pins are user I/O on a different device that is in the migration path,the Quartus II software ensures the pins are not used as user I/O in the Quartus II software. Ensure that these pins are connected

Figure 2–5. Cyclone LE



Each LE's programmable register can be configured for D, T, JK, or SR operation. Each register has data, true asynchronous load data, clock, clock enable, clear, and asynchronous load/preset inputs. Global signals, general-purpose I/O pins, or any internal logic can drive the register's clock and clear control signals. Either general-purpose I/O pins or internal logic can drive the clock enable, preset, asynchronous load, and asynchronous data. The asynchronous load data input comes from the `data3` input of the LE. For combinatorial functions, the LUT output bypasses the register and drives directly to the LE outputs.

Each LE has three outputs that drive the local, row, and column routing resources. The LUT or register output can drive these three outputs independently. Two LE outputs drive column or row and direct link routing connections and one drives local interconnect resources. This allows the LUT to drive one output while the register drives another output. This feature, called register packing, improves device utilization because the device can use the register and the LUT for unrelated

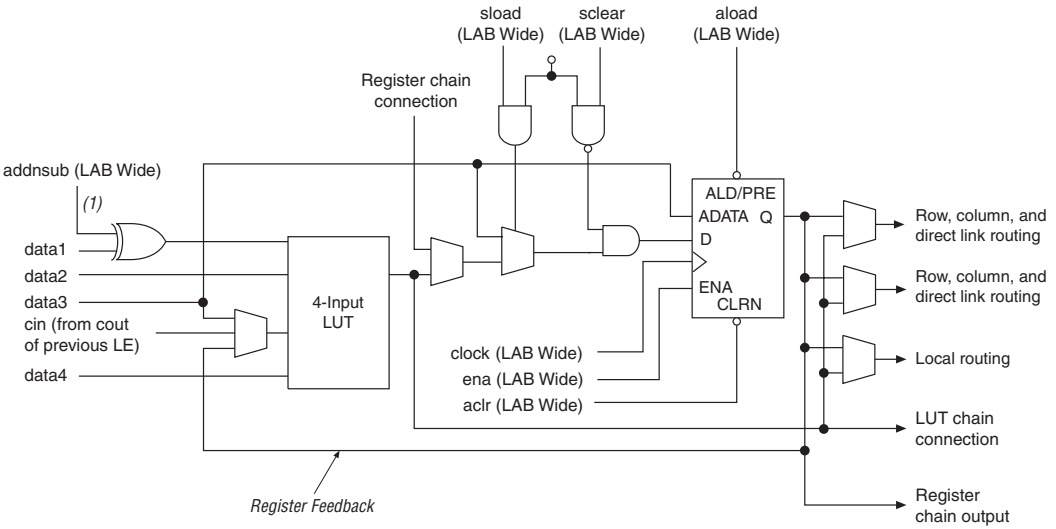
preset/load, synchronous clear, synchronous load, and clock enable control for the register. These LAB-wide signals are available in all LE modes. The `addnsub` control signal is allowed in arithmetic mode.

The Quartus II software, in conjunction with parameterized functions such as library of parameterized modules (LPM) functions, automatically chooses the appropriate mode for common functions such as counters, adders, subtractors, and arithmetic functions. If required, you can also create special-purpose functions that specify which LE operating mode to use for optimal performance.

Normal Mode

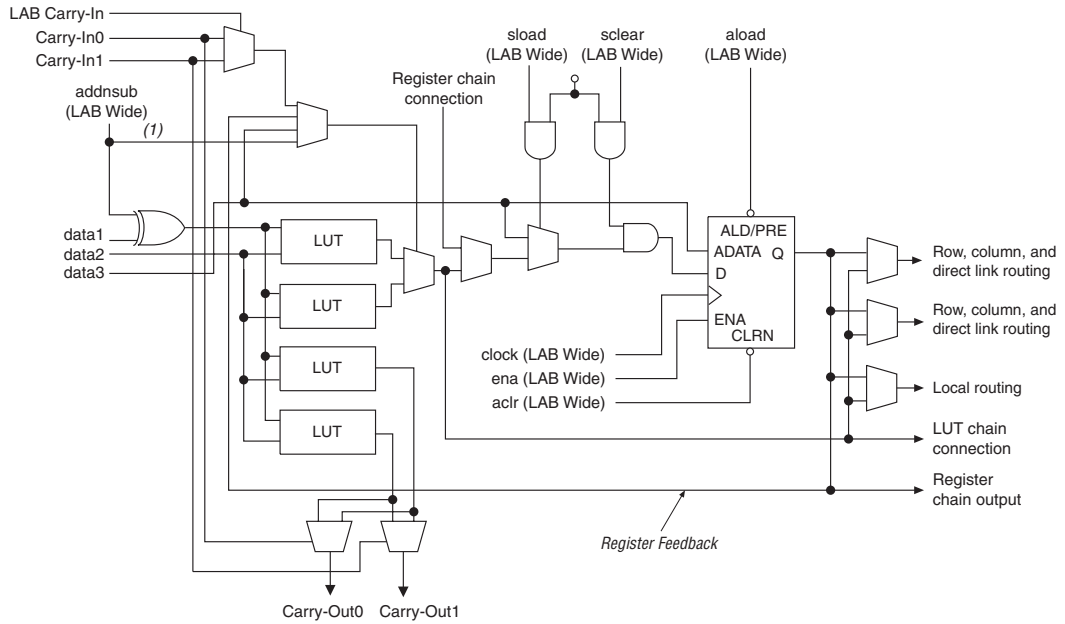
The normal mode is suitable for general logic applications and combinatorial functions. In normal mode, four data inputs from the LAB local interconnect are inputs to a four-input LUT (see Figure 2–6). The Quartus II Compiler automatically selects the carry-in or the `data3` signal as one of the inputs to the LUT. Each LE can use LUT chain connections to drive its combinatorial output directly to the next LE in the LAB. Asynchronous load data for the register comes from the `data3` input of the LE. LEs in normal mode support packed registers.

Figure 2–6. LE in Normal Mode



Note to Figure 2–6:
(1) This signal is only allowed in normal mode if the LE is at the end of an adder/subtractor chain.

Figure 2–7. LE in Dynamic Arithmetic Mode



Note to Figure 2–7:
(1) The `addnsub` signal is tied to the carry input for the first LE of a carry chain only.

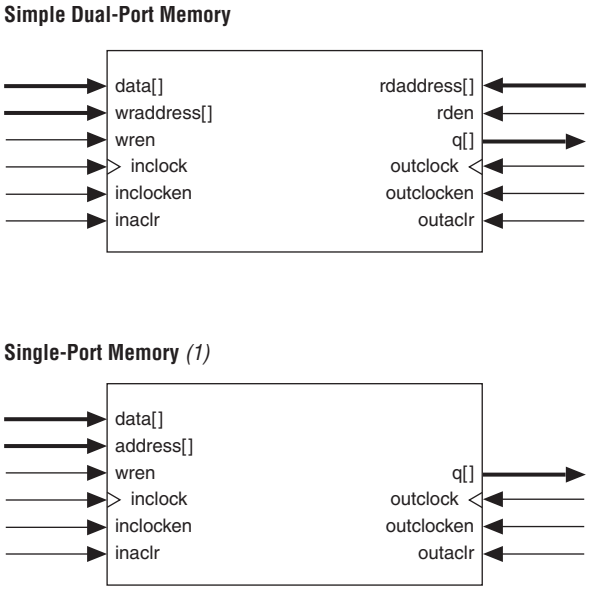
Carry-Select Chain

The carry-select chain provides a very fast carry-select function between LEs in dynamic arithmetic mode. The carry-select chain uses the redundant carry calculation to increase the speed of carry functions. The LE is configured to calculate outputs for a possible carry-in of 0 and carry-in of 1 in parallel. The `carry-in0` and `carry-in1` signals from a lower-order bit feed forward into the higher-order bit via the parallel carry chain and feed into both the LUT and the next portion of the carry chain. Carry-select chains can begin in any LE within a LAB.

The speed advantage of the carry-select chain is in the parallel pre-computation of carry chains. Since the LAB carry-in selects the precomputed carry chain, not every LE is in the critical path. Only the propagation delays between LAB carry-in generation (LE 5 and LE 10) are now part of the critical path. This feature allows the Cyclone architecture to implement high-speed counters, adders, multipliers, parity functions, and comparators of arbitrary width.

In addition to true dual-port memory, the M4K memory blocks support simple dual-port and single-port RAM. Simple dual-port memory supports a simultaneous read and write. Single-port memory supports non-simultaneous reads and writes. Figure 2–13 shows these different M4K RAM memory port configurations.

Figure 2–13. Simple Dual-Port and Single-Port Memory Configurations



Note to Figure 2–13:

(1) Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The memory blocks also enable mixed-width data ports for reading and writing to the RAM ports in dual-port RAM configuration. For example, the memory block can be written in ×1 mode at port A and read out in ×16 mode from port B.

The Cyclone memory architecture can implement fully synchronous RAM by registering both the input and output signals to the M4K RAM block. All M4K memory block inputs are registered, providing synchronous write cycles. In synchronous operation, the memory block generates its own self-timed strobe write enable (`wren`) signal derived from a global clock. In contrast, a circuit using asynchronous RAM must generate the RAM `wren` signal while ensuring its data and address signals meet setup and hold time specifications relative to the `wren`

signal. The output registers can be bypassed. Pseudo-asynchronous reading is possible in the simple dual-port mode of M4K blocks by clocking the read enable and read address registers on the negative clock edge and bypassing the output registers.

When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.

Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The Quartus II software automatically implements larger memory by combining multiple M4K memory blocks. For example, two 256×16-bit RAM blocks can be combined to form a 256×32-bit RAM block. Memory performance does not degrade for memory blocks using the maximum number of words allowed. Logical memory blocks using less than the maximum number of words use physical blocks in parallel, eliminating any external control logic that would increase delays. To create a larger high-speed memory block, the Quartus II software automatically combines memory blocks with LE control logic.

Parity Bit Support

The M4K blocks support a parity bit for each byte. The parity bit, along with internal LE logic, can implement parity checking for error detection to ensure data integrity. You can also use parity-size data words to store user-specified control bits. Byte enables are also available for data input masking during write operations.

Shift Register Support

You can configure M4K memory blocks to implement shift registers for DSP applications such as pseudo-random number generators, multi-channel filtering, auto-correlation, and cross-correlation functions. These and other DSP applications require local data storage, traditionally implemented with standard flip-flops, which can quickly consume many logic cells and routing resources for large shift registers. A more efficient alternative is to use embedded memory as a shift register block, which saves logic cell and routing resources and provides a more efficient implementation with the dedicated circuitry.

The size of a $w \times m \times n$ shift register is determined by the input data width (w), the length of the taps (m), and the number of taps (n). The size of a $w \times m \times n$ shift register must be less than or equal to the maximum number of memory bits in the M4K block (4,608 bits). The total number of shift

Figure 2–15. M4K RAM Block Control Signals

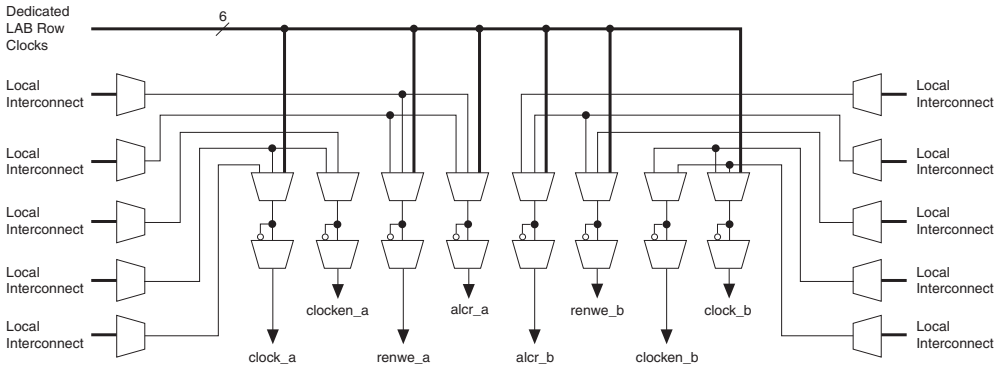
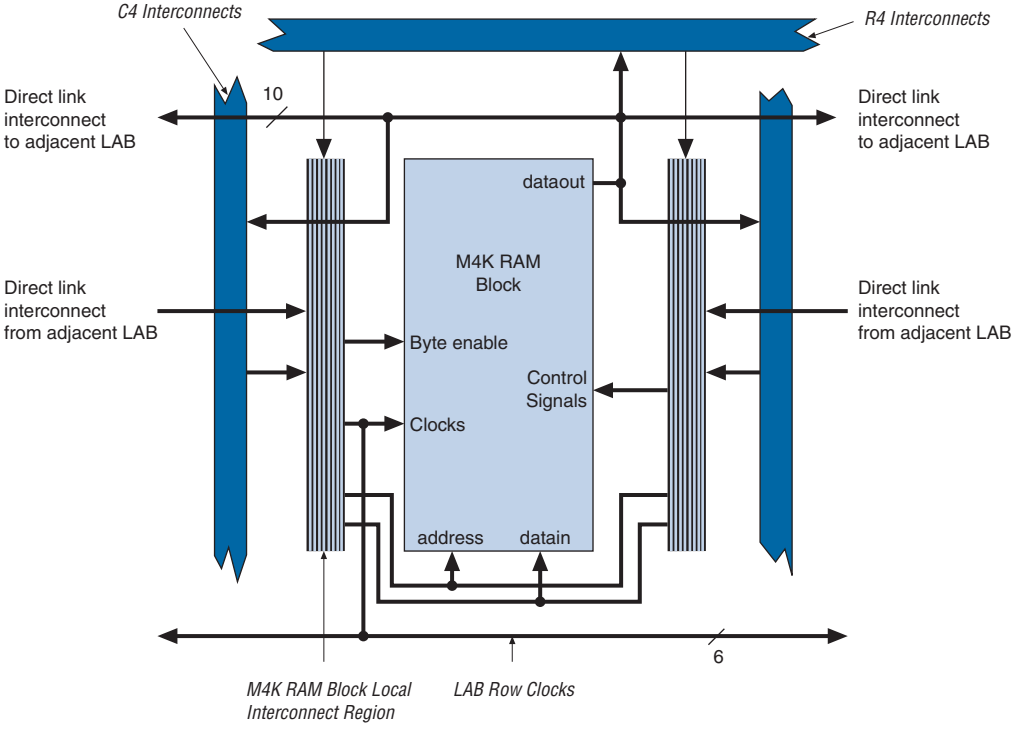


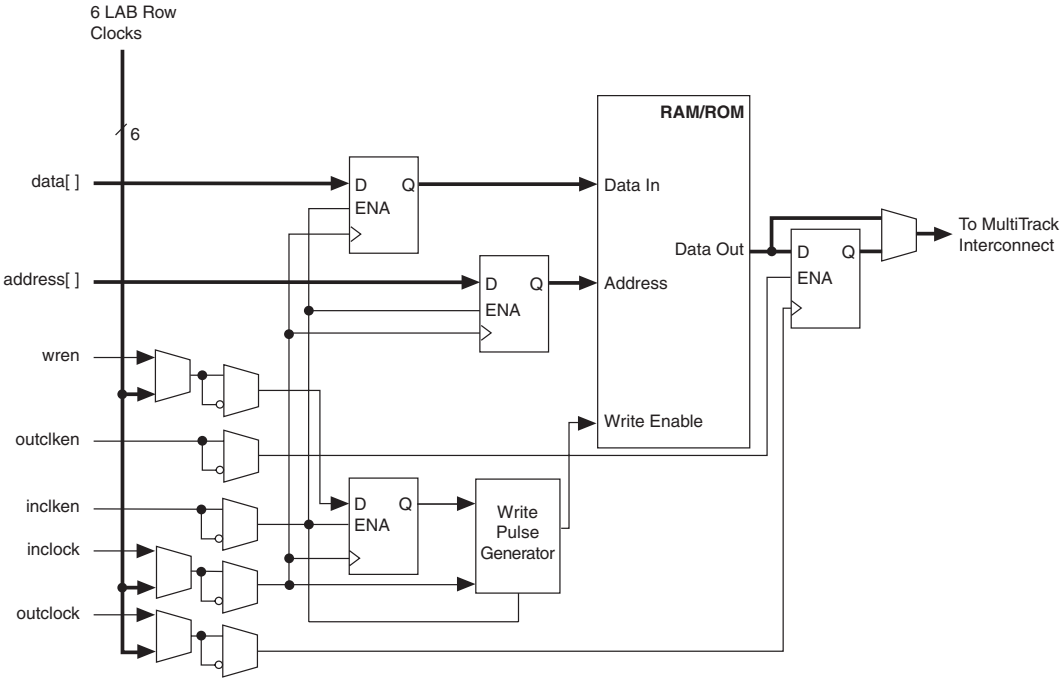
Figure 2–16. M4K RAM Block LAB Row Interface



Single-Port Mode

The M4K memory blocks also support single-port mode, used when simultaneous reads and writes are not required. See Figure 2–21. A single M4K memory block can support up to two single-port mode RAM blocks if each RAM block is less than or equal to 2K bits in size.

Figure 2–21. Single-Port Mode *Note (1)*



Note to Figure 2–21:

(1) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Global Clock Network and Phase-Locked Loops

Cyclone devices provide a global clock network and up to two PLLs for a complete clock management solution.

Global Clock Network

There are four dedicated clock pins (`CLK[3..0]`, two pins on the left side and two pins on the right side) that drive the global clock network, as shown in Figure 2–22. PLL outputs, logic array, and dual-purpose clock (`DPCLK[7..0]`) pins can also drive the global clock network.

External Clock Inputs

Each PLL supports single-ended or differential inputs for source-synchronous receivers or for general-purpose use. The dedicated clock pins (CLK[3..0]) feed the PLL inputs. These dual-purpose pins can also act as LVDS input pins. See Figure 2–25.

Table 2–8 shows the I/O standards supported by PLL input and output pins.

Table 2–8. PLL I/O Standards

I/O Standard	CLK Input	EXTCLK Output
3.3-V LVTTL/LVCMOS	✓	✓
2.5-V LVTTL/LVCMOS	✓	✓
1.8-V LVTTL/LVCMOS	✓	✓
1.5-V LVCMOS	✓	✓
3.3-V PCI	✓	✓
LVDS	✓	✓
SSTL-2 class I	✓	✓
SSTL-2 class II	✓	✓
SSTL-3 class I	✓	✓
SSTL-3 class II	✓	✓
Differential SSTL-2	—	✓

For more information on LVDS I/O support, refer to "LVDS I/O Pins" on page 2–54.

External Clock Outputs

Each PLL supports one differential or one single-ended output for source-synchronous transmitters or for general-purpose external clocks. If the PLL does not use these PLL_OUT pins, the pins are available for use as general-purpose I/O pins. The PLL_OUT pins support all I/O standards shown in Table 2–8.

The external clock outputs do not have their own V_{CC} and ground voltage supplies. Therefore, to minimize jitter, do not place switching I/O pins next to these output pins. The EP1C3 device in the 100-pin TQFP package

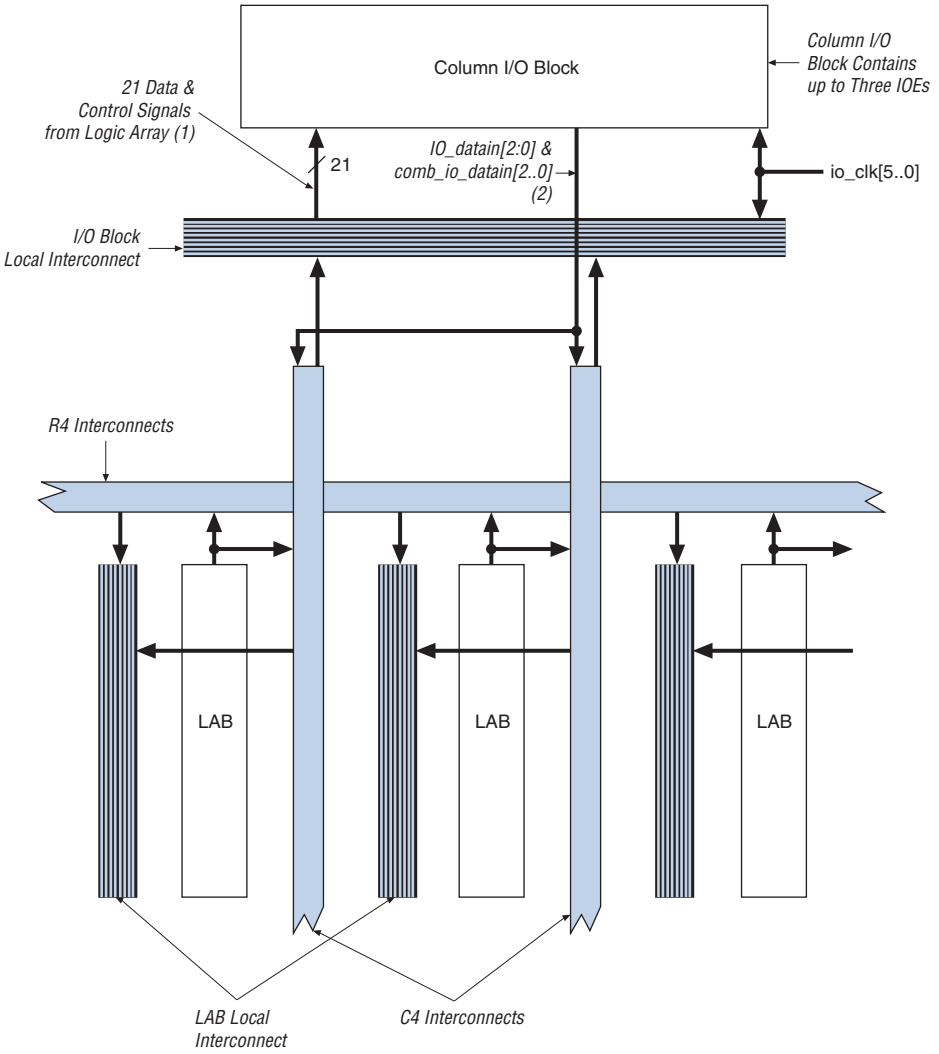
I/O Structure

IOEs support many features, including:

- Differential and single-ended I/O standards
- 3.3-V, 64- and 32-bit, 66- and 33-MHz PCI compliance
- Joint Test Action Group (JTAG) boundary-scan test (BST) support
- Output drive strength control
- Weak pull-up resistors during configuration
- Slew-rate control
- Tri-state buffers
- Bus-hold circuitry
- Programmable pull-up resistors in user mode
- Programmable input and output delays
- Open-drain outputs
- DQ and DQS I/O pins

Cyclone device IOEs contain a bidirectional I/O buffer and three registers for complete embedded bidirectional single data rate transfer. Figure 2–27 shows the Cyclone IOE structure. The IOE contains one input register, one output register, and one output enable register. You can use the input registers for fast setup times and output registers for fast clock-to-output times. Additionally, you can use the output enable (OE) register for fast clock-to-output enable timing. The Quartus II software automatically duplicates a single OE register that controls multiple output or bidirectional pins. IOEs can be used as input, output, or bidirectional pins.

Figure 2–29. Column I/O Block Connection to the Interconnect



Notes to Figure 2–29:

(1) The 21 data and control signals consist of three data out lines, `io_dataout[2..0]`, three output enables, `io_coe[2..0]`, three input clock enables, `io_cce_in[2..0]`, three output clock enables, `io_cce_out[2..0]`, three clocks, `io_cclk[2..0]`, three asynchronous clear signals, `io_caclr[2..0]`, and three synchronous clear signals, `io_csclr[2..0]`.

(2) Each of the three IOEs in the column I/O block can have one `io_datain` input (combinatorial or registered) and one `comb_io_datain` (combinatorial) input.

Table 2–10. DQ Pin Groups (Part 2 of 2)

Device	Package	Number of ×8 DQ Pin Groups	Total DQ Pin Count
EP1C6	144-pin TQFP	4	32
	240-pin PQFP	4	32
	256-pin FineLine BGA	4	32
EP1C12	240-pin PQFP	4	32
	256-pin FineLine BGA	4	32
	324-pin FineLine BGA	8	64
EP1C20	324-pin FineLine BGA	8	64
	400-pin FineLine BGA	8	64

Note to Table 2–10:
(1) EP1C3 devices in the 100-pin TQFP package do not have any DQ pin groups in I/O bank 1.

A programmable delay chain on each DQS pin allows for either a 90° phase shift (for DDR SDRAM), or a 72° phase shift (for FCRAM) which automatically center-aligns input DQS synchronization signals within the data window of their corresponding DQ data signals. The phase-shifted DQS signals drive the global clock network. This global DQS signal clocks DQ signals on internal LE registers.

These DQS delay elements combine with the PLL's clocking and phase shift ability to provide a complete hardware solution for interfacing to high-speed memory.

The clock phase shift allows the PLL to clock the DQ output enable and output paths. The designer should use the following guidelines to meet 133 MHz performance for DDR SDRAM and FCRAM interfaces:

- The DQS signal must be in the middle of the DQ group it clocks
- Resynchronize the incoming data to the logic array clock using successive LE registers or FIFO buffers
- LE registers must be placed in the LAB adjacent to the DQ I/O pin column it is fed by

Figure 2–34 illustrates DDR SDRAM and FCRAM interfacing from the I/O through the dedicated circuitry to the logic array.

Each I/O bank can support multiple standards with the same V_{CCIO} for input and output pins. For example, when V_{CCIO} is 3.3-V, a bank can support LVTTL, LVCMOS, 3.3-V PCI, and SSTL-3 for inputs and outputs.

LVDS I/O Pins

A subset of pins in all four I/O banks supports LVDS interfacing. These dual-purpose LVDS pins require an external-resistor network at the transmitter channels in addition to 100-Ω termination resistors on receiver channels. These pins do not contain dedicated serialization or deserialization circuitry; therefore, internal logic performs serialization and deserialization functions.

Table 2–13 shows the total number of supported LVDS channels per device density.

Table 2–13. Cyclone Device LVDS Channels

Device	Pin Count	Number of LVDS Channels
EP1C3	100	*(1)*
	144	34
EP1C4	324	103
	400	129
EP1C6	144	29
	240	72
	256	72
EP1C12	240	66
	256	72
	324	103
EP1C20	324	95
	400	129

Note to Table 2–13:

(1) EP1C3 devices in the 100-pin TQFP package do not support the LVDS I/O standard.

MultiVolt I/O Interface

The Cyclone architecture supports the MultiVolt I/O interface feature, which allows Cyclone devices in all packages to interface with systems of different supply voltages. The devices have one set of V_{CC} pins for internal operation and input buffers (V_{CCINT}), and four sets for I/O output drivers (V_{CCIO}).

The Cyclone V_{CCINT} pins must always be connected to a 1.5-V power supply. If the V_{CCINT} level is 1.5 V, then input pins are 1.5-V, 1.8-V, 2.5-V, and 3.3-V tolerant. The V_{CCIO} pins can be connected to either a 1.5-V, 1.8-V, 2.5-V, or 3.3-V power supply, depending on the output requirements. The output levels are compatible with systems of the same voltage as the power supply (i.e., when V_{CCIO} pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). When V_{CCIO} pins are connected to a 3.3-V power supply, the output high is 3.3-V and is compatible with 3.3-V or 5.0-V systems. Table 2–14 summarizes Cyclone MultiVolt I/O support.

Table 2–14. Cyclone MultiVolt I/O Support *Note (1)*

V_{CCIO} (V)	Input Signal					Output Signal				
	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V
1.5	✓	✓	✓ (2)	✓ (2)	—	✓	—	—	—	—
1.8	✓	✓	✓ (2)	✓ (2)	—	✓ (3)	✓	—	—	—
2.5	—	—	✓	✓	—	✓ (5)	✓ (5)	✓	—	—
3.3	—	—	✓ (4)	✓	✓ (6)	✓ (7)	✓ (7)	✓ (7)	✓	✓ (8)

Notes to Table 2–14:

(1) The PCI clamping diode must be disabled to drive an input with voltages higher than V_{CCIO}.
(2) When V_{CCIO} = 1.5-V or 1.8-V and a 2.5-V or 3.3-V input signal feeds an input pin, higher pin leakage current is expected. Turn on **Allow voltage overdrive for LVTTL / LVCMOS input pins** in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combinations.
(3) When V_{CCIO} = 1.8-V, a Cyclone device can drive a 1.5-V device with 1.8-V tolerant inputs.
(4) When V_{CCIO} = 3.3-V and a 2.5-V input signal feeds an input pin, the V_{CCIO} supply current will be slightly larger than expected.
(5) When V_{CCIO} = 2.5-V, a Cyclone device can drive a 1.5-V or 1.8-V device with 2.5-V tolerant inputs.
(6) Cyclone devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
(7) When V_{CCIO} = 3.3-V, a Cyclone device can drive a 1.5-V, 1.8-V, or 2.5-V device with 3.3-V tolerant inputs.
(8) When V_{CCIO} = 3.3-V, a Cyclone device can drive a device with 5.0-V LVTTL inputs but not 5.0-V LVCMOS inputs.

Power Sequencing and Hot Socketing

Because Cyclone devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the V_{CCIO} and V_{CCINT} power supplies may be powered in any order.

Signals can be driven into Cyclone devices before and during power up without damaging the device. In addition, Cyclone devices do not drive out during power up. Once operating conditions are reached and the device is configured, Cyclone devices operate as specified by the user.

Table 3–1. Cyclone JTAG Instructions (Part 2 of 2)

JTAG Instruction	Instruction Code	Description
USERCODE	00 0000 0111	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	00 0000 0110	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
HIGHZ *(1)*	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.
CLAMP *(1)*	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions	—	Used when configuring a Cyclone device via the JTAG port with a MasterBlaster™ or ByteBlasterMV™ download cable, or when using a Jam File or Jam Byte-Code File via an embedded processor.
PULSE_NCONFIG	00 0000 0001	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.
CONFIG_IO	00 0000 1101	Allows configuration of I/O standards through the JTAG chain for JTAG testing. Can be executed before, after, or during configuration. Stops configuration if executed during configuration. Once issued, the CONFIG_IO instruction will hold nSTATUS low to reset the configuration device. nSTATUS is held low until the device is reconfigured.
SignalTap II instructions	—	Monitors internal device operation with the SignalTap II embedded logic analyzer.

Note to Table 3–1:
(1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

In the Quartus II software, there is an Auto Usercode feature where you can choose to use the checksum value of a programming file as the JTAG user code. If selected, the checksum is automatically loaded to the USERCODE register. Choose Assignments > Device > Device and Pin Options > General. Turn on **Auto Usercode**.

Table 4–13. SSTL-3 Class I Specifications (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{REF}	Reference voltage	—	1.3	1.5	1.7	V
V_{IH}	High-level input voltage	—	V_{REF} + 0.2	—	V_{CCIO} + 0.3	V
V_{IL}	Low-level input voltage	—	–0.3	—	V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = –8 mA *(11)*	V_{TT} + 0.6	—	—	V
V_{OL}	Low-level output voltage	I_{OL} = 8 mA *(11)*	—	—	V_{TT} – 0.6	V

Table 4–14. SSTL-3 Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage	—	3.0	3.3	3.6	V
V_{TT}	Termination voltage	—	V_{REF} – 0.05	V_{REF}	V_{REF} + 0.05	V
V_{REF}	Reference voltage	—	1.3	1.5	1.7	V
V_{IH}	High-level input voltage	—	V_{REF} + 0.2	—	V_{CCIO} + 0.3	V
V_{IL}	Low-level input voltage	—	–0.3	—	V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = –16 mA *(11)*	V_{TT} + 0.8	—	—	V
V_{OL}	Low-level output voltage	I_{OL} = 16 mA *(11)*	—	—	V_{TT} – 0.8	V

Table 4–15. Bus Hold Parameters

Parameter	Conditions	V_{CCIO} Level								Unit
		1.5 V		1.8 V		2.5 V		3.3 V		
		Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	$V_{IN} > V_{IL}$ (maximum)	—	—	30	—	50	—	70	—	µA
High sustaining current	$V_{IN} < V_{IH}$ (minimum)	—	—	–30	—	–50	—	–70	—	µA
Low overdrive current	0 V < V_{IN} < V_{CCIO}	—	—	—	200	—	300	—	500	µA
High overdrive current	0 V < V_{IN} < V_{CCIO}	—	—	—	–200	—	–300	—	–500	µA

Typically, the user-mode current during device operation is lower than the power-up current in Table 4–17. Altera recommends using the Cyclone Power Calculator, available on the Altera web site, to estimate the user-mode I_{CCINT} consumption and then select power supplies or regulators based on the higher value.

Timing Model

The DirectDrive technology and MultiTrack interconnect ensure predictable performance, accurate simulation, and accurate timing analysis across all Cyclone device densities and speed grades. This section describes and specifies the performance, internal, external, and PLL timing specifications.

All specifications are representative of worst-case supply voltage and junction temperature conditions.

Preliminary and Final Timing

Timing models can have either preliminary or final status. The Quartus® II software issues an informational message during the design compilation if the timing models are preliminary. Table 4–18 shows the status of the Cyclone device timing models.

Preliminary status means the timing model is subject to change. Initially, timing numbers are created using simulation results, process data, and other known parameters. These tests are used to make the preliminary numbers as close to the actual timing parameters as possible.

Final timing numbers are based on actual device operation and testing. These numbers reflect the actual performance of the device under worst-case voltage and junction temperature conditions.

Table 4–18. Cyclone Device Timing Model Status

Device	Preliminary	Final
EP1C3	—	✓
EP1C4	—	✓
EP1C6	—	✓
EP1C12	—	✓
EP1C20	—	✓

Performance

The maximum internal logic array clock tree frequency is limited to the specifications shown in Table 4–19.

Table 4–19. Clock Tree Maximum Performance Specification

Parameter	Definition	-6 Speed Grade			-7 Speed Grade			-8 Speed Grade			Units
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Clock tree f_{MAX}	Maximum frequency that the clock tree can support for clocking registered logic	—	—	405	—	—	320	—	—	275	MHz

Table 4–20 shows the Cyclone device performance for some common designs. All performance values were obtained with the Quartus II software compilation of library of parameterized modules (LPM) functions or megafunctions. These performance values are based on EP1C6 devices in 144-pin TQFP packages.

Table 4–20. Cyclone Device Performance

Resource Used	Design Size and Function	Mode	Resources Used			Performance		
			LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)
LE	16-to-1 multiplexer	—	21	—	—	405.00	320.00	275.00
	32-to-1 multiplexer	—	44	—	—	317.36	284.98	260.15
	16-bit counter	—	16	—	—	405.00	320.00	275.00
	64-bit counter *(1)*	—	66	—	—	208.99	181.98	160.75

Table 4–24. Routing Delay Internal Timing Microparameter Descriptions	
Symbol	**Parameter**
t_{R4}	Delay for an R4 line with average loading; covers a distance of four LAB columns
t_{C4}	Delay for an C4 line with average loading; covers a distance of four LAB rows
t_{LOCAL}	Local interconnect delay

Figure 4–1 shows the memory waveforms for the M4K timing parameters shown in Table 4–23.

Figure 4–1. Dual-Port RAM Timing Microparameter Waveform